EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3925	(716/4-6).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:43
L2	17	corner adj capacitance	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:44
L3	1446	delay adj3 curve	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:44
L4	35063	transition adj point	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:44
L5	5	2 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:44
L6	5	4 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:45
S1	550	delay adj curve	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/13 13:41
S2	17	corner adj capacitance	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:43

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S3	33764	transition adj point	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:38
S4	2036079	region	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:38
S5	11435	curvilinear and linear	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:39
S6	4926	S4 and S5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:39
S7	8	S1 and S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:40
S8	5	S2 and S3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:40
S9	4	S7 and S8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:39
S10	5	S1 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/30 13:42

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S11	1203	(716/6).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/13 13:41

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3	(characteriz$3 and timing and delay and curve and first and region and second and region and equation and corner adj capacitance).clm.	US-PGPUB; USPAT	OR	ON	2006/03/22 15:18

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1 Session 1D:issues in timing estimation: Miller factor for gate-level coupling delay calculation
Pinhong Chen, Desmond A. Kirkpatrick, Kurt Keutzer
November 2000 **Proceedings of the 2000 IEEE/ACM international conference on Computer-aided design**
Publisher: IEEE Press
Full text available: pdf(129.32 KB) Additional Information: full citation, abstract, references, citings

In coupling delay computation, a *Miller factor* of more than 2X may be necessary to account for active coupling capacitance when modeling the delay of deep submicron circuitry in the presence of active coupling capacitance. We propose an efficient method to estimate this factor such that the delay response of a *decoupling circuit model* can emulate the original coupling circuit. Under the assumptions of zero initial voltage, equal charge transfer, and 0.5*VDD* as the ...

2 Weibull Based Analytical Waveform Model
Chirayu S. Amin, Florentin Dartu, Yehea I. Ismail
November 2003 **Proceedings of the 2003 IEEE/ACM international conference on Computer-aided design**
Publisher: IEEE Computer Society
Full text available: pdf(255.51 KB) Additional Information: full citation, abstract, index terms

Current CMOS technologies are characterized by interconnectlines with increased relative resistance w.r.t. driver outputresistance. Designs generate signal waveshapes that are verydifficult to model using a single parameter model such as thetransition time. In this paper, we present a simple and robustparameter analytical expression for waveform modeling based onthe Weibull cumulative distribution function. The Weibull modelaccurately captures the variety of waveshapes without introducingsignifi ...

3 A new gate delay model for simultaneous switching and its applications
Liang-Chi Chen, Sandeep K. Gupta, Melvin A. Breuer
June 2001 **Proceedings of the 38th conference on Design automation**
Publisher: ACM Press
Full text available: pdf(163.26 KB) Additional Information: full citation, abstract, references, citings, index terms

4 Leakage power optimization: Statistical optimization of leakage power considering process variations using dual-Vth and sizing
Ashish Srivastava, Dennis Sylvester, David Blaauw